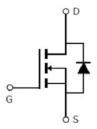


Main Product Characteristics

| V _{DSS} | 100V |
|----------------------|--------------|
| R _{DS} (on) | 3.0mΩ (typ.) |
| I _D | 180A ① |



1, Gate 2~3,5~7 Source 4,8 Drain



TO-263-7L

Pin Assignment

Schematic diagram

Features and Benefits

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating

| Symbol | Parameter | Max. | Units |
|---------------------------------|--|-------------|-------|
| I _D @ TC = 25°C | Continuous Drain Current, V _{GS} @ 10V | 180 ① | |
| I _D @ TC = 100°C | Continuous Drain Current, V _{GS} @ 10V | 130 ① | Α |
| I _{DM} | Pulsed Drain Current ② | 670 | |
| P _D @TC = 25°C | Power Dissipation ③ | 375 | W |
| PD @ 1C = 25 C | Linear Derating Factor | 2.5 | W/°C |
| V _{DS} | Drain-Source Voltage | 100 | V |
| V_{GS} | Gate-to-Source Voltage | ± 20 | V |
| E _{AS} | Single Pulse Avalanche Energy @ L=0.3mH | 1045 | mJ |
| I _{AS} | Avalanche Current @ L=0.3mH | 83.5 | А |
| T _J T _{STG} | Operating Junction and Storage Temperature Range | -55 to +175 | °C |



Thermal Resistance

| Symbol | Characterizes | Тур. | Max. | Units |
|-------------------|---|------|------|-------|
| R ₀ JC | Junction-to-case ③ | _ | 0.4 | °C/W |
| В | Junction-to-ambient (t \leq 10s) \oplus | _ | 62 | °C/W |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB mounted, steady-state) ④ | | 40 | °C/W |

Electrical Characterizes @T_A=25℃ unless otherwise specified

| Symbol | Parameter | Min. | Тур. | Max. | Units | Conditions |
|----------------------|--------------------------------------|------|------|------|----------------------------|---|
| V _{(BR)DSS} | Drain-to-Source breakdown voltage | 100 | _ | _ | V | $V_{GS} = 0V$, $I_{D}= 1mA$ |
| R _{DS(on)} | Static Drain-to-Source on-resistance | _ | 3.0 | 4.0 | mΩ | V _{GS} =10V,I _D =110A |
| V _{GS(th)} | Gate threshold voltage | 2.0 | _ | 4.0 | V | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ |
| | Drain to Source leakage current | _ | _ | 1 | | V _{DS} =100V, V _{GS} = 0V |
| I _{DSS} | Drain-to-Source leakage current | _ | _ | 50 | μA | T _J = 125°C |
| | Cata to Source forward lookege | _ | _ | 100 | - Λ | V _{GS} =20V |
| I _{GSS} | Gate-to-Source forward leakage | _ | _ | -100 | nA | V _{GS} = -20V |
| Qg | Total gate charge | _ | 224 | _ | | I _D = 50A, |
| Q _{gs} | Gate-to-Source charge | _ | 80 | _ | nC | V _{DS} =50V, |
| Q_{gd} | Gate-to-Drain("Miller") charge | _ | 55 | _ | | V _{GS} = 10V |
| t _{d(on)} | Turn-on delay time | _ | 40 | _ | | V _{GS} =10V, V _{DD} =65V, |
| t _r | Rise time | _ | 141 | _ | 20 | R _L =0.87Ω, |
| t _{d(off)} | Turn-Off delay time | _ | 95 | _ | nS R_{GEN} =2.6 Ω | |
| t _f | Fall time | _ | 101 | _ | | I _D =75A |
| C _{iss} | Input capacitance | _ | 5634 | _ | | V _{GS} = 0V |
| Coss | Output capacitance | _ | 657 | _ | pF | V _{DS} = 50V |
| C _{rss} | Reverse transfer capacitance | _ | 12.6 | _ | | f = 1MHz |

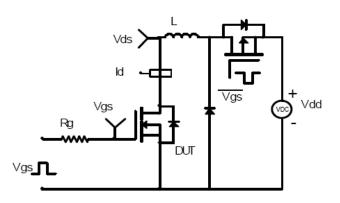
Source-Drain Ratings and Characteristics

| Symbol | Parameter | Min. | Тур. | Max. | Units | Conditions |
|-----------------|---------------------------|------|------|-------|-------|---|
| | Continuous Source Current | | _ | 180 ① | А | MOSFET symbol |
| Is | (Body Diode) | _ | | | | showing the |
| I _{SM} | Pulsed Source Current | | | 670 | А | integral reverse |
| | (Body Diode) | _ | | | | p-n junction diode. |
| V _{SD} | Diode Forward Voltage | _ | 0.75 | 1.3 | V | I _S =20A, V _{GS} =0V, T _J = 25°C |

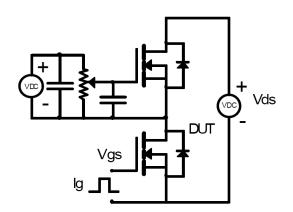


Test circuits and Waveforms

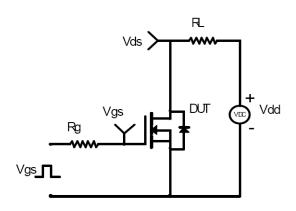
EAS Test Circuit:



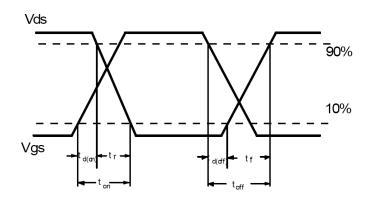
Gate charge test circuit:



Switching Time Test Circuit:



Switching Waveforms:



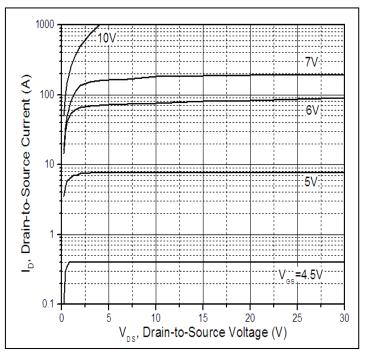
Version: 1.2

Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\texttt{6JA}}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



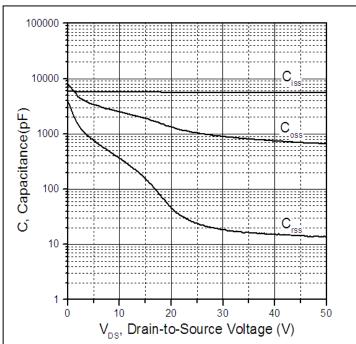


Figure 1: Typical Output Characteristics

Figure 2. Typical Capacitance Vs. Drain-to-Source Voltage

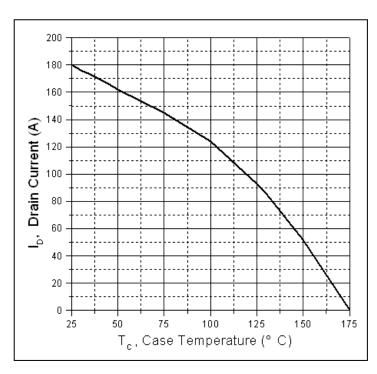


Figure 3. Maximum Drain Current Vs. Case Temperature

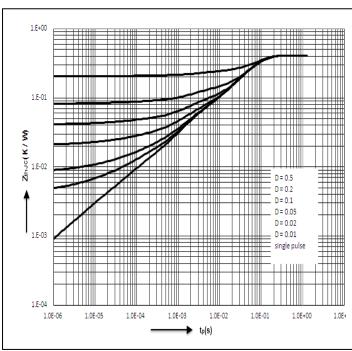
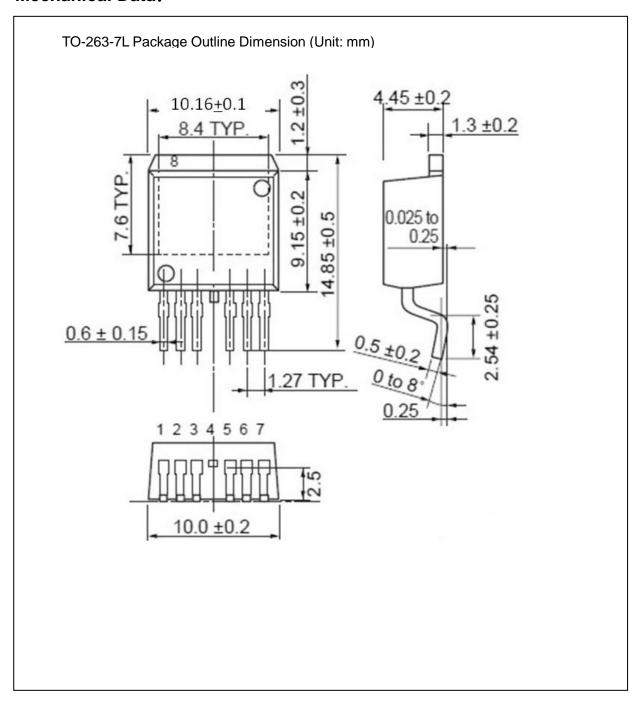


Figure 4. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:





Ordering and Marking Information

Device Marking: SSS1004A7

Package (Available)
TO-263-7L
Operating Temperature Range
C: -55 to 175 °C

Devices per Unit

| Package | Units/ | Tubes/Inner | Units/Inner | Inner | Units/Carton |
|---------|--------|-------------|-------------|--------------|--------------|
| Туре | Tube | Box | Box | Boxes/Carton | Box |
| | | | | | |
| | | | | Box | |

Reliability Test Program

| Test Item | Conditions | Duration | Sample Size |
|-------------|--|------------|---------------------|
| High | T _j =175℃ @ 80% of | 168 hours | 3 lots x 77 devices |
| Temperature | Max V _{DSS} /V _{CES} /VR | 500 hours | |
| Reverse | | 1000 hours | |
| Bias(HTRB) | | | |
| High | T _j =175℃ @ 100% of | 168 hours | 3 lots x 77 devices |
| Temperature | Max V _{GSS} | 500 hours | |
| Gate | | 1000 hours | |
| Bias(HTGB) | | | |



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